1	Original Research Article
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3	Electric Parameters Degradation of Monocrystalline Silicon
4	Photovoltaic Cells/modules: Temperature and Heat Effects
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8	Abstract:
9	Temperature is extremely significant to the PV modules degradation process,
10	especially hot spots, encapsulant bleaching, delamination failure on
11	interconnections, corrosion, discoloration, and bubbles on the panel's surface.
12	Aims: We investigated analytically the electrical parameters degradation of
13	monocrystalline silicon PV cells/modules under temperature and heat effect.
14	Study Design: Laboratory of Radiation Physics LPR, FAST-UAC, 01 BP 526,
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16	Science (FDSM), University of Abomey-Calavi, Benin.
17	Methodology: Servant model has been exploited using the wind velocity under
18	standard irradiation conditions ( $G=1000w/m^2$ ) in the 298-353K temperature range.
19	The single exponential model has been used to extract the PV cell parameters from a
20	single (J–V) characteristic curve at various values of T.
21	<b>Results:</b> The results obtained show that $(J_{Ph})$ increase exponentially from 7.67% to

22 65.87%. with temperature. ( $R_s$ ) increase linearly by 7.6% and 9.18% while ( $V_{oc}$ )

decrease from 19.4 % to 17.6% and  $(R_{sh})$  decrease approximately by 12.6% and 4.8%.

The obtained power output (P) losses had been 82.31 % and 31.56%, and the overall linear losses in efficiency ( $\eta$ ) had been approximately 27.84% and 5.02 %, while ( $J_S$ ) increase exponentially from 3.87% to 15.75%.

**Conclusion:** The increase in  $(J_{ph})$  with temperature can be attributed to the increased in light absorption owing to a decrease in the bandgap of silicon. The decrease in  $(\eta)$  with temperature is mainly controlled by the decrease in  $(V_{oc})$  and fill factor (FF) with T.

Keywords: Degradation process; temperature and heat effect; Servant model;
light absorption, decrease in the bandgap.

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#### 35 **1. Introduction**

PV cells/modules know many degradation processes due to their exposure to temperature, atmospheric pressure, humidity, long time ultraviolet (UV) illumination, mechanical shock, precipitations, dust, wind and snow; which reduce the intrinsic lifetime of these cells very short. The limited lifetime is a result of several processes that are in play simultaneously [1, 2].

The vellowing, delamination, bubbles, breakage and cracks in the cells, defects in the 41 anti-reflective coating, burnt cells, discoloration, and corrosion are the visible and 42 dominant factors [1, 3-8]. Besides these direct defects, temperature can accelerate 43 many degradation processes. The temperature plays then an important role in the 44 photovoltaic cells/modules conversion process. The performance of these PV 45 cells/modules decreases with increasing of the temperature, due to increased 46 internal carrier recombination rates, caused by increased carrier concentrations [6]. 47 In addition, combined effects (temperature and humidity; temperature and light; 48 temperature, dust and humidity; light, humidity and dust) are factors of PV 49 cells/modules degradation in almost all identified degradation modes [1-7]. 50

The majority of studies on the crystalline Silicon (c-Si) technology report that the 51 calculated P<sub>max</sub> degradation has been mainly attributed to short circuit current 52 density  $(J_{SC})$  losses, followed by smaller decreases in the fill factor (FF).  $J_{SC}$ 53 degradation associated with the reduction of  $P_{max}$  has been most commonly caused 54 by delamination and discoloration [8-13]. [12] Showed that the reduction in  $J_{SC}$  was 55 due to discoloration or delamination at the cell/ethylene vinyl acetate (EVA) 56 interface, front glass breakage and increased series resistance  $(R_s)$ , due to the 57 degradation in electrode soldering. Interconnect degradation in crystalline silicon 58 modules occurs when the joined cell-to-ribbon or ribbon-to-ribbon area changes in 59 structure or in geometry. The characteristics directly attributable to interconnect 60 degradation include increased series resistance (Rs) in the electrical circuit, 61 increased heating in the module, and localized hot spots causing burns at the solder-62 joints, at the polymer back sheet, and in the encapsulate [13,14]. 63

64 The identification of the origin of degradation and failure modes and how they affect 65 the photovoltaic cells/modules is necessary to improve the reliability of photovoltaic

66 installations. However, despite the identification of PV modules degradation modes,

- it is still difficult to study them in real conditions. To overcome the obstacles of the
- 68 long-term experiences, some analytical models have been elaborated in recent years,
- 69 in order to study the degradation of the PV cells/modules under real conditions or
- not, since this depends on the aim at [1, 5, 15].
- In this work, we used the Servant model under standard irradiation conditions to
  study analytically, the electrical parameters degradation of monocrystalline silicon
  PV cells under temperature and heat effect. The PV cell parameters have been
  extracted using the single exponential model in the 298-353K temperature range.
- Moreover, the environmental and climatic conditions in which the modules areexposed significantly influence the performance of these PV cells.
- This paper is organized as follows. In Section 2, a visual inspection of PV modules degradation observed has been indexed. Subsequently, light-induced degradation, thermal degradation, electrical parameters models, and cell temperature models have been established and presented. Next, the results are analyzed and discussed in section 3. Finally, in section 4, the conclusions and our perspectives are enumerated.
- 82

#### 83 2. Materials and Methods

#### 84 **2.1. Visual degradation**

Delamination is very frequent in hot and humid climates. It causes moisture penetration in the PV module and therefore induces various chemical and physical degradations such as metal corrosion of the module structure most frequently. Delamination is more severe if it occurs in the borders of the module because, a part from the power losses causes electrical risks to the module and the installation. Delamination is also related to a transmittance loss, as materials are not well optically coupled and a part of the light escapes [16-19] (**Fig.1**).



Fig.1. (a) PV module délamination; (b)-(C) severe delamination (this
figure presents an example of how an extreme delamination could
destroy a PV module when the defect appeared after barely a year of
functioning) [1, 16, 17]

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The corrosion attacks the metallic connections of PV cells causing a loss of performance by increasing leakage currents. Corrosion also degrades the adhesion between cells and metallic frame [3]. [20] Have been found out that corrosion appeared after 1000h of exposure of PV module under 85°C and 85% of relative humidity. Corrosion and discoloration are the predominant modes of photovoltaic modules degradation [3, 5] (**Fig.2**).



# Fig.2. (a) PV module a fected by corrosion at the edge and the junction box [3]; (b) Solar cells discolored [1, 19]

Module discoloration is a change in color of material which turns yellow and sometimes brown. It modifies transmittance of light reaching PV cells and therefore the power generated by the module is reduced. In addition, discoloration degrades the short-circuit current (*Isc*) of PV module. This degradation may vary from 6% to 8% below the nominal value for a partial discoloration of the PV module surface and from 10% to 13% for complete discoloration [1, 4, 21, 22, 23]. The Maximum power (P<sub>max</sub>) of the PV module is also degraded by module discoloration.

Glass breakage is one of an important degradation factor of PV cells/modules. 120 Breakages and cracks are usually followed by other degradation types such as 121 122 corrosion, delamination and discoloration [1, 13, 20] (Fig.3). Our investigations 123 shown that, it is generally impossible to detect cracks on the already operational PV module to the naked eye. This detection can be done by using optical methods [24]. 124 This method essentially consists of applying an intense wideband light (1000 suns) 125 and detecting the path where the light passes through the cell or, on the contrary, is 126 blocked due to the reflections that can cause a crack. 127

128





*Fig.4.Image showing how a hot spot can damage a PV cell/module* [26]
Thermal analysis has been used to detect a hot spot defect. This analysis could be performed in normal operation. In this case, the PV module could be operating in a solar plant. Another thermal test consists of the operation of the PV module at extreme conditions (short-circuit conditions). In this case, the module should work alone, and the electrical connectors positive and negative of the module are short-circuited [1, 26].

Bubbles are generally due to chemical reactions that emit gases trapped in the PVcell/module (Fig.5).



Fig.5. (a) Bubbles on the back side of a PV module [1, 3]; (b) Bubbles on
 the front side of a PV module [24].

Bubbles located on the module front side produce a reduction of the radiation 167 reaching the module. Which cause a decoupling of the light and increase reflection 168 [3]. This kind of defect is similar to delamination, but in this case, the lack of 169 170 adherence of the EVA affects only a small area and is combined with the blowing of areas where this adherence has been lost. These defects appear in the center of the 171 cell and may be due to poor adhesion of the cell caused by the high temperature. [1, 172 3].When bubbles occur in the back side of the PV module, a bulk appears in the 173 174 polymeric encapsulant or the back cover, forming a bubble. Bubbles make the heat dissipation of the cells more difficult, overheating them and subsequently reducing 175 the lifetime of these cells. Bubbles have been detected using IR techniques [27], as 176 they are not visible though visual inspection alone but rather cause a temperature 177 178 change (Fig.5). In addition, the bubble forms an air chamber, and although the air

temperature in the chamber appears lower than in the adjacent cells, the cell 179 temperature is actually higher because the heat of the cell is less dissipated 180 [26].Moreover, the yellowing and browning cause a change in the transmittance of 181 the light reaching the solar cells and thus a decrease in the power generated. The 182 main cause of these defects in EVA and in ethylene copolymer films is UV radiation 183 and water exposure combined with temperatures above 50 °C that induce a change in 184 the chemical structure of the polymer [21]. In some PV cells/modules, yellowing 185 appears in some areas but not in adjacent areas with a different polymeric 186 encapsulant of a different origin or characteristics. During the life of the PV module, 187 the anti-reflective coating (ARC) receives radiation that could induce a change in the 188 ARC coloring. The anti-reflective properties may suffer changes in this case. The light 189 that reaches the cells may be lower than expected. Nonetheless, this colour change 190 should not cause a decrease in the wavelength radiation that the cell uses, but rather 191 only affect a part of the visible radiation. Anti-reflection coating is one of the light 192 management techniques to reduce reflection loss of solar light. When the light passes 193 through the interface between two media with different refractive index, partial light 194 195 will be reflected back. In terms of solar cells, reflection will occur at device surface 196 and each interfaces. Such reflected light will not be converted into electricity [28]. A follow-up of the affected modules should be done in order to detect whether this 197 defect leads to another more severe defect [10].Detachment of the frame, lines and 198 blemishes in the cells are the other factors detected. 199

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## 201 2.2. Light-Induced Degradation

Possible degradation mechanisms under irradiance are presented in Fig.6. Light 202 203 induced degradation is one of the main ageing mechanisms. More research is required to understand the mechanisms and kinetics of PV module discoloration as 204 well as the induced power losses. Besides discoloration, bubbles are another concern 205 for encapsulant photo-thermal degradation. In the process of photochemical 206 207 degradation, gases of different types can be generated with a potential to cause delamination which can enhance water ingress and cause further problems such as 208 209 decoupling of light transmission and reduction of heat dissipation. Another problematic reaction product generated during photochemical ageing is acid such as 210 acetic acid and carbon dioxides. 211

The acidification may form electrolytes leading to metallization corrosion. It may 212 also cause increased conductivity of the encapsulant which can result in increase 213 leakage current. In addition, for the influences of irradiance on encapsulation 214 materials, UV light has the most destructive effects. UV light is a primary initiator for 215 many reactions such as the photodecomposition, photo thermal and photo bleaching. 216 In contrast to discoloration, there is another UV-light induced effect called photo-217 bleaching as a result of photo-oxidation. With sufficient oxygen and at a high enough 218 temperature, the yellowed polyenes can be oxidized generating products that are 219 more visibly clear. Photo-bleaching can lead to a colour changing of EVA from yellow 220 back to clear. Besides the photodegradation of the base material, additives within 221 EVA will decompose under UV light, generating free radicals that accelerate base 222 EVA photodecomposition. The generated products may be chromophores that can 223 worsen EVA discoloration [29-32]. 224



Fig.6. Light-induced degradation

#### 230 2.3. Thermally-Induced Degradation

The temperature of cells/modules is usually higher than ambient temperature. 231 Moreover, thermal effect acts as an accelerating factor for degradations caused by 232 humidity or irradiance. Thermal cycles can reduce module reliability in a number of 233 ways. For glass, residual strains may exist after lamination which can result breakage 234 or delamination between glass/pottant under thermal strains. For encapsulant, 235 236 different photo-thermal and thermal reactions can happen together with UV radiation from light. The principal reactions of EVA are what called Norrish I and 237 Norrish II. In Norrish I, the vinyl acetate group can take off from the main chain to 238 form acetaldehyde together with some gases which have potential to further lead to 239 bubbles in the module. In Norrish II, C=C bonds (polyenes) are formed which have 240 been widely considered as the chromophores group for EVA discoloration. Besides 241 that, acetic acid is produced to catalyze discoloration and corrosion reaction. 242



The polyenes produced in Norrish II can further be oxidized to form  $\alpha$ - $\beta$  unsaturated 250 carbonyl, another product leading to discoloration [6, 33, 34]. Besides chemical 251 reactions, polymer may also undergo morphology changes under high temperature. 252 Cells can also suffer from thermal fatigue with reported cracking and solder joint 253 degradation. With regards to interfaces, the thermal heterogeneity of different 254 materials can induce cracks, bubbles and delamination under daily thermal cycles. 255 Besides these direct defects, temperature can accelerate many degradation processes. 256 The water diffusion through polymers has been reported to be accelerated by 257 258 temperature in the Arrhenius form [35]. Other procedures like metallization 259 corrosion, leakage current, diffusion of dopants, impurities, occur more rapidly at 260 higher temperature.

261

#### 262 **2.4. Electrical parameters models**

Most of the electrical parameters of PV modules depend on the temperature and the solar irradiation. Once all these parameters are determined within reference conditions, their new values can be determined in any real operating conditions [36-42], using the following models (1)-(19) indexed.

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### 268 **2.4.1. Photocurrent density** $(J_{ph})$

In most of the studies, the photocurrent density  $(J_{ph})$  is approximated by the short circuit current density [38, 43, 44]. This assumption is generally accepted for the modeling of PV module or cell because in real devices the series resistance is low while the parallel resistance is high. This parameter is often considered as a good starting point in several refined iterative algorithms [39].

274 
$$J_{ph}(G,T) = J_{ph_{ref}} \Big[ 1 + \alpha_{Jsc} \Big( T_m - T_{ref} \Big) \Big] \frac{G}{G_{ref}}$$
(1)

275 Where  $T_{ref}$ : solar cell temperature in reference condition, $G_{ref}$ : solar irradiation in 276 reference condition, G: solar irradiation,  $T_m$ : module temperature, $\alpha_{Jsc}$ : Temperature 277 coefficient of the short-circuit current density (available in the module data sheet), 278  $J_{ph_{ref}}$ : short-circuit current density in the reference conditions.

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#### 280 **2.4.2. Saturation current density** $(J_S)$

The rates of the saturation current density change with the cell temperature according to equations (2, 3) and (4, 5) for one-diode [38] and two-diode model [39, 45] respectively. Authors report that the equations are suitable for all technology ofsilicon solar cells [38, 39, 45].

285 
$$J_{S} = J_{S_{ref}} \times \left(\frac{T_{m}}{T_{ref}}\right)^{3} \times exp\left(\frac{1}{K}\left(\frac{E_{g_{ref}}}{T_{ref}} - \frac{E_{g}(T_{m})}{T_{m}}\right)\right)$$
(2)

286

289

$$\frac{E_g(T)}{E_{g_{ref}}} = 1 - 0.0002677 \left( T_m - T_{ref} \right)$$
(3)

287 
$$J_{S_i} = J_{S_{ref}} \times \left(\frac{T_m}{T_{ref}}\right)^{\frac{3}{ni}} \times exp\left(\left(\frac{E_g(T)}{ni.K}\right)\left(\frac{1}{T_{ref}} - \frac{1}{T_m}\right)\right)$$
(4)

288 with i = 1, 2

$$E_g(T) = 1.17 - 0.000673 \times \frac{T_m^2}{T_m + 636}$$
(5)

with  $J_{S_{ref}}$ ,  $J_S$  the saturation current density in reference and real conditions respectively, K: Boltzmann constant (J. $K^{-1}$ ),  $E_g$ (eV): Gap of the semi-conductor material in the real conditions is linked for one-diode model to the gap in reference conditions by expression (5) which has been widely used for silicon solar [38]: The value of  $E_{g_{ref}}$  for the silicon solar cells at STC conditions is equal to 1.121eV [38].

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### 296 **2.4.3. Series** $(R_S)$ and shunt $(R_{Sh})$ resistance

Several methods have been used to calculate series  $(R_S)$  and shunt  $(R_{Sh})$  resistance 297 values at non STC conditions from their reference values (data known at given 298 299 conditions) [38, 46]. In general, the methods require material (semi-conductor) 300 characteristic coefficients. These latters vary from one module to another and must 301 be experimentally determined. To simplify the calculation, some authors assume that  $R_{\rm s}$  is independent of incident irradiation and temperature for both one-diode models 302 [36, 47, 48] and two-diode model [39, 49]. It has been reported that shunt resistance 303 304 is inversely proportional to the solar irradiance [36, 37, 50]. [39, 51] have shown that this earlier assumption is true only at very low light intensities while  $R_{sh}$  is 305 considered independent of temperature and can be set constant for  $G > 100 \text{ W/m}^2$ . 306 307 Unfortunately, these two assumptions lead to bad results with [42] modeling 308 especially for two-diode models. It seems that the right way to determine  $R_s$ andR<sub>sh</sub>should take into account the thermal parameters of the material. Nevertheless, 309 the following methods [36-38] give good results for the two types of model. 310

311 
$$\frac{R_S}{R_{S_{ref}}} = \frac{T_m}{T_{ref}} \left( 1 - \beta \times ln \frac{G}{G_{ref}} \right)$$
(6)

where  $\beta$ , is a coefficient which value is approximately 0.217 and  $R_{S_{ref}}$ : Series 312 resistance in the reference conditions 313

314

$$R_{Sh_{ref}} = R_{Sh} \times \frac{G}{G_{ref}} \tag{7}$$

In addition, Series resistance is known to affect Fill factor (FF) adversely. [52] Have 315 316 observed that Rs decreases more rapidly with T in the low temperature region (100-317 250 K) in poly silicon cells as compared to that in single-crystal cells. [53] Have found that R<sub>S</sub> increases with temperature. [54] Have found that ideality factor n of a solar 318 cell decreases with T. Earlier studies [55, 56] have ignored the effect of temperature 319 dependence of Rsh on  $dV_{OC}/dT$  and that of temperature dependence of Rs on (FF) 320 321 and are applicable only for higher efficiency cells which have very low Rs and very 322 large  $R_{Sh}$  values. We have noticed that in case of cells having screen-printed contacts solar cells  $R_S$  may be high and  $R_{Sh}$  may be low and both may vary with T significantly. 323

324

#### 2.4.4. Open-circuit voltage(V<sub>oc</sub>) 325

The main temperature dependence in solar cells arises from variation of three main 326 parameters, which are usually used to characterize the solar cell outputs, these 327 are: J<sub>SC</sub>, the short-circuit current density, which usually has a negative sign, the open-328 circuit voltage  $V_{OC}$  which in principal is characterized by  $J_S$ , the diode saturation 329 330 current, and n, the diode ideality factor, and the fill factor FF, which in turn is a function of  $V_{OC}$ .  $V_{OC}$  is given as follows [57]: 331

332

$$V_{OC} = \frac{n \, k \, T_m}{q} \ln \left[ 1 - \frac{G_{Sh} V_{OC}}{J_S} + \frac{J_{ph}}{J_S} \right] \tag{8}$$

Where  $J_S$ : is a function of material properties and it is also sensitive to temperature. 333

According to Eq. (9),  $T_m$ : module temperature. We expect a linear dependence of  $V_{oc}$ 334

on temperature, if  $J_{ph} \gg G_{Sh}V_{OC}$  and  $J_{ph} \gg J_S$ , then, we have: 335

$$V_{OC} = \frac{E_g}{q} - \frac{n \, k \, T_m}{q} \ln q$$

$$V_{OC} = \frac{E_g}{q} - \frac{n k T_m}{q} \ln \left( \frac{J_S}{J_{ph}} \right)$$
  
E<sub>g</sub>: Bandgap energy of the absorber material.

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#### 2.4.5. PV module efficiency models 339

The performance of a solar cell is influenced by temperature as its performance 340 341 parameters: open-circuit voltage ( $V_{OC}$ ), short-circuit current density ( $J_{SC}$ ), fill factor (FF) and efficiency  $(\eta)$  are temperature dependent. It has been shown earlier that V<sub>OC</sub> 342

(9)

decreases at a rate of 2.3 mV/K whereas  $J_{SC}$  increases slightly with temperature ( $T_m$ ). (FF) also decreases and all these lead to an overall decrease in the cell efficiency [58]. It turns out that both the open circuit voltage and the fill factor decrease substantially with temperature (as the thermally excited electrons begin to dominate the electrical properties of the semi-conductor), while the short-circuit current increases, but only slightly [58, 59]. All these effects lead to a linear relation in the form:

$$\eta = \eta_{T_{ref}} \left[ 1 - \beta_{ref} \left( T_m - T_{ref} \right) + \gamma \log_{10} G_T \right]$$
(10)

350  $\eta_{T_{ref}}$ : Module electrical efficiency at the reference temperature,  $T_m$ : PV module 351 temperature,  $T_{ref}$ : Reference temperature at solar radiation flux of 1000W/m<sup>2</sup>, 352  $\beta_{ref} = \frac{1}{T_0 + T_{ref}}$ : Temperature coefficient (depends not only on the PV material but 353 on $T_{ref}$ ), $\gamma$ : Solar radiation coefficient and  $T_0$ : the high temperature at which the PV 354 module's electrical efficiency drops to zero [58, 60, 61].

A reduced expression of the model has been proposed by [62], neglecting the solarradiation coefficient (for a weak solar radiation):

$$\eta = \eta_{T_{ref}} \left[ 1 - \beta_{ref} \left( T_m - T_{ref} \right) \right] \tag{11}$$

In these analytical models, the cell/module temperature which is not readily available has been replaced by the nominal operating cell temperature ( $T_{NOCT}$ ) and we have [63]:

362 
$$\eta = \eta_{ref} \left\{ 1 - \beta_{ref} \left[ T_a - T_{ref} + (T_{NOCT} - T_a) \frac{G_T}{G_{NOCT}} \right] \right\}$$
(12)

363 In which

364 
$$T_{a} = T_{m} - \left(\frac{G_{T}}{G_{NOCT}}\right) \left(\frac{U_{LNOCT}}{U_{L}}\right) \left(T_{NOCT} - T_{a,NOCT}\right) \left[1 - \left(\frac{\eta_{c}}{\tau\alpha}\right)\right]$$
(13)

An analytical model of the monthly average efficiency has been proposed by [64], inorder to estimated the monthly electrical energy output of a PV array.

367 
$$\bar{\eta} = \eta_{Tref} \left[ -1 - \beta_{ref} \left( \overline{T_a} - T_{ref} \right) - \frac{\beta_{ref} (\overline{\tau \alpha}) \overline{H_T V}}{n U_L} \right]$$
(14)

Where, n: Number of hours per day, $U_L$ :overall thermal loss coefficient,  $\overline{H}_T$ : the monthly average daily insolation on the plane of the array,  $\overline{V}$ : a dimensionless function of such quantities as the sunset angle.

371

#### 372 **2.4.6.** PV module power output models

The prediction of PV module performance in terms of electrical power output in the field, that is, the deviation from the standard test conditions reported by the manufacturer of the module, is analytically modeled in a manner analogous to the module efficiency.Recently, [65] proposed a correlation for PV module power, similar in form to Eq. (11).

$$P = G_T \tau_{pV} \eta_{ref} A \left[ 1 - 0.0045 (T_m - 25) \right]$$
(15)

379  $\tau_{pV}$ ; Transmittance of the PV cell outside layers

A nonlinear multivariable regression model has been proposed by [66], resulting from an analysis which addresses the fact that the cells within a module are not identical

383 
$$P_{mp} = d_1 G_T + d_2 T_m + d_3 [\ln(G_T)]^m + d_4 T_m [\ln(G_T)]^m$$

384 In which "m' are model parameters.

Another unusual nonlinear correlation has been proposed by [67], giving a correction coefficient for the output power as defined by Eq. (17) of a water cooled PV system:.

388

$$P_m = V_m I_m = (FF) \times V_{OC} \times I_{SC}$$
(17)

$$P = V_C I_C \left[ 1 - \frac{G_T - 500}{2 \times 10^4} + \frac{C_{T_C}}{4 \times 10^4} \times (50 - T_m)^2 \right]$$
(18)

390  $I_c$  and  $V_c$  are the output voltage and current respectively

391

The wind speed is taken into account in several correlations for the efficiency[58, 66,68-71].

394

$$P = G_T (b_1 + b_2 G_T + b_3 T_a + b_4 V_f)$$
(19)

In which  $V_f$ : represents the free-stream local wind speed, measured at a height of 10m above ground,  $b_j$ , j = 1, 4: regression coefficients, are determined using solar radiation flux values above 500W/m<sup>2</sup>.

Besides, [68] review the methods proposed in the literature to determine the operating temperatures of the modules. These models can be classified into implicit and explicit.

The implicit model is based on the knowledge of the thermal properties of the module and their heat transfer mechanisms. An energy balance in the module is thus considered, from which it is possible to determine its instantaneous operation temperature. The practical application of this type of models is very complicated, as they require the module to be in a steady state. This is difficult to meet under real

(16)

operating conditions, and the temperature of the module greatly depends on the
meteorological parameters, which are continuously changing, and the thermal
processes that occur in the different materials that make up the module [72].

The explicit methods calculate the operating temperature of the module using known
parameters. Thus, the simplest expression is the one that uses the nominal operating
cell temperature, which is widely used and supplied by the module manufacturers.
This temperature is defined under specific meteorological conditions that are difficult
to meet under real conditions [58, 73].

414

#### 415 **2.5. Cell temperature models**

The cell temperature is a function of the ambient temperature  $T_a$  and the solar irradiation G. It is generally approximated with the following expression [57, 58, 74].

$$T_m = T_{amb} + \frac{G}{800} \left( T_{NOCT} - 293.15^{\circ} K \right)$$
(20)

419  $T_{NOCT}$ : Nominal temperature of the PV cells at a solar irradiation of 800 W/m<sup>-2</sup>, an 420 ambient temperature of 20°C and a wind speed of 1ms<sup>-1</sup>.

421

In practice, the sizing in many PV systems and the simulation of their operating is carried out using hourly and, sometimes, even daily values [75]. [76] Puts forward another model to obtain the temperature of the module based on a simplified model of the heat exchange between the PV module and the atmosphere. All these models work with instantaneous value of all the parameters and predict the value of the temperature of the module for a specific instant.

428

#### 429 **2.5.1. Servant model**

This model is based on the heat exchange between the PV module and the atmosphere. He allows obtaining the temperature of the module according to meteorological parameters [76].

433 
$$T_m = T_{amb} + d \times G \times (1 + e \times T_{amb})(1 - fW)$$
(21)

434 435

## where W: the wind speed, d, e and f : Parameters that are calculated empirically.

#### 436 **2.5.2. Ross model**

Based on the thermal properties of the module when steady state, [77] proposes a
model where the difference between the temperature of the module and the ambient
temperature is directly proportional to the incident irradiance:

440 
$$T_m = T_{amb} + K \times G \tag{22}$$

K: the Ross coefficient depends, among other factors, on the technology of themodule, its shape and size, encapsulation, assembly and environmental conditions.

443

#### 444 **2.5.3. King model**

In order to offset the influence that wind speed has on the temperature of the
module, a ratio between the module temperature, the incident irradiance and the
wind speed has been proposed [58].

$$T_m = T_{amb} + G \times e^{(m+n.W)}$$
(23)

G: Incident solar irradiance on the surface of the module, *m*: Dimensionless empirical coefficient that describes the impact of the irradiance on the temperature of the module, establishing the upper limit of the temperature of the module at low wind speeds and high irradiances, *n*: Empirical coefficient that describes the cooling of the module because of the wind; in other words, the speed at which the temperature of the module drops as the wind speed increases.

#### 456 **2.5.4. Mattei model**

This model is based on the energy balance that takes place in the module. The temperature of a module according to this model is given by the following expression [72]:

455

$$T_m = \frac{U_{PV}T_{amb} + G\left[(C_\alpha \tau) - \eta_r - \gamma \eta_r T_r\right]}{U_{PV} - \gamma \eta_r G}$$
(24)

461 where  $U_{PV} = p + qW$ : Heat exchange coefficient of the module depending on the wind 462 speed,  $C_{\alpha}$ : Cell absorption coefficient,  $\tau$ : Glass transmittance,  $\eta_r$ : The efficiency of the 463 module at the benchmark temperature  $T_r = 25^{\circ}C$  and at an irradiance of 1000W/m<sup>2</sup> 464 and  $\gamma$ : The absolute value of the variation coefficient of the power with the 465 temperature of module in %C.

466

Two new models have been proposed that, based on the standard NOCT model,
means that the influence of the wind speed on the operating temperature of the
module can be introduced.

470 🚸

### NOCT-1p model

The NOCT model assumes that wind speed is always 1m/s. When a module is exposed to real sunlight, the wind speed has many different values. Therefore, this model takes into account the impact of the wind speed on the temperature of the module.

475 
$$T_m = T_{amb} + \frac{G}{800 W/m^2} (NOCT - 20^{\circ}C) + a (W + W_1)$$
(25)

476 where  $W_1$ : The benchmark wind speed that appears in the definition of the NOCT 477 temperature ( $W_1=1m/s$ ), W: Wind speed in m/s and a: an empirical parameter, 478 expressed in °*C*. *s*.  $m^{-1}$ . These values are determined in the experimental fitting of the 479 data.

480 **\* NOCT-2p model** 

This model takes into account the relationship between the temperature increase andthe incident irradiance.

483

$$T_m = T_{amb} + b \left[ \frac{G}{800 W m^{-2}} (NOCT - 20^{\circ}C) \right] + C (W + W_1)$$
(26)

Where b: Dimensionless parameter, C: has the same dimensions and meaning as inthe previous model.

#### 486 **2.5.5. Hourly models**

Using the previously described instantaneous models, new models have been built where the baseline data are the hourly values of the different meteorological variables that appear in each of the models. These new hourly models are proposed both for the previously existing instantaneous models and for the ones proposed by [74]. The hourly value is the average value of all the instantaneous measurements recorded in that hour, except for the hourly irradiation that is the integral of the irradiance values logged in that time interval.

#### 494

#### 495 **2.5.5.1. Hourly nominal operating cell temperature model**

496

$$T_{m-h} = T_{amb-h} + \frac{H}{800 Wh/m^2} (NOCT - 20^{\circ}C)$$
(27)

497 where,  $T_{m-h}$ : The average temperature of the module in one hour (°C),  $T_{amb-h}$ : The 498 hourly mean of the ambient temperature (°C), H : The hourly irradiation received by 499 the module (Wh/m<sup>2</sup>). 500

#### 501 2.5.5.2. Hourly Servant model

502

$$T_{m-h} = T_{amb-h} + d_h H \left(1 + e_h T_{amb-h}\right) \left(1 - f_h W_h\right)$$
(28)

503  $W_h$ : Hourly average of the wind speed,  $d_h$ ,  $e_h$  and  $f_h$  the parameters to be determined 504 that will now,  $d_h$  have different units to the constant of the instantaneous model. 505

506 **2.5.5.3. Hourly Ross model** 

507 
$$T_{m-h} = T_{amb-h} + k_h H$$
 (29)

513

508  $k_h$ : The empirical coefficient expressed in (°C.m<sup>2</sup>/Wh).

#### 510 **2.5.5.4. Hourly King model**

[78] Proposed a modification to the equation (23), for instantaneous values, in orderto eliminate the dimensional inconsistency.

$$T_{m-h} = T_{amb-h} + \frac{T_0}{H_0} H \left( e^{m_h + n_h W_h} \right)$$
(30)

514  $T_o$  and  $H_o$ : are the ambient temperature and irradiation in standard measurement 515 conditions,  $m_h$  and  $n_h$  are now the parameters to be determined. 516

517 If the equation of King's instantaneous model, Eq (23), had been applied, the hourly518 expression obtained would be as follows:

519 
$$T_{m-h} = T_{amb-h} + \frac{T_0}{H_0} H \left( e^{m_{h-h} + n_{h-h} W_{h-h}} \right)$$
(31)

520 Where  $m_{h-h}$  and  $n_{h-h}$  represent the values of those parameters in King's original 521 model. Matching the Eqs (30) and (31), the following relationships have been 522 obtained:

523 
$$\begin{cases} n_{h-h} = n_h \\ m_{h-h} = m_h - \ln \frac{H_0}{T_0} = m_h - \ln 40 \end{cases}$$
(32)

524

#### 525 2.5.5.5. Hourly Mattei model

526 
$$T_m = \frac{(P_h + q_h W_h) T_{amb-h} + H \left[ (C_a \tau)_h - \eta_r - \gamma \eta_{r T_r} \right]}{P_k + q_h W_h - \gamma \eta_{r H}}$$
(33)

527 Where  $(C_{\alpha}\tau)_h$ : the new empirical coefficients to be determine, that continues to be 528 dimensionless,  $P_h$ : expressed in  $(Wh.m^{-2} \circ C^{-1})$  and  $q_h$  expressed in 529  $(Wh.s.m^{-3} \circ C^{-1})$ .

530

## 531 **2.5.5.6. Hourly NOCT-1p model.**

$$T_{m-h} = T_{amb-h} + \frac{H}{800 Wh/m^2} (NOCT - 20^{\circ}C) + a_h (W_k - W_1)$$
(34)

Where  $W_1 = 1m/s$  and  $a_h$ : the parameter to be determined in (°C. s.  $m^{-1}$ ). When  $W_h = 1$ , this model coincides with the NOCT model.

535

#### 536 **2.5.5.7. Hourly NOCT-2p model.**

537 
$$T_{m-h} = T_{amb-h} + b_h \left[ \frac{H}{800 W m^{-2}} (NOCT - 20^{\circ}C) \right] + C_h (W_h + W_1)$$
(35)

538 Where  $b_h$  continues to be a dimensionless parameter and  $C_h$  is expressed in (°C. 539 s. $m^{-1}$ ). 540



574 
$$J = J_{ph} - J_{S} \left[ exp \left( \frac{q(V + R_{S}J)}{nK_{B}T} \right) - 1 \right] - \frac{(V + R_{S}J)}{R_{Sh}}$$
(37)

575 Therefore, the transcendental analytic equation for the optimal current-density  $J_{opt}$  of the 576 ideal PV module is described by [35]:

577 
$$J_{opt} = \frac{J_{Ph} + J_S}{1 + \frac{1}{\ln\left(\frac{J_{Ph} - J}{J_S}\right) + 1}}$$
(38)

578 with, 
$$V_{opt} = \frac{k T_m}{q} \ln \left( \frac{J_{Ph} - J}{J_S} + 1 \right)$$
 (39)

579 Where  $J_{Ph}(A/cm^2)$ : the photoinduced current-density determined by the spectral 580 composition, intensity, and concentration of incident solar radiation and also by the efficiency 581 of assembling photogenerated p-n junction charge carriers,  $J_S(A/cm^2)$ : the reverse dark 582 photoinduced saturation current-density determined by potential and electro-physical 583 parameters of p-n junction,  $T_m(^{\circ}K)$ : PV module temperature, k: the Boltzmann constant; and 584 q(C) is the electron charge.

585 When the PV module is illuminated by solar light  $J_{Ph} \gg J_S$ ,  $J_{Ph} - J \gg J_S$ , the logarithm in 586 the denominator of  $J_{opt}$  is a higher value and does not vary much with variations in J. Then, 587 the transcendental equation is solved by stepwise approximations. For J = 0, we have:

$$J_{opt} = \frac{J_{Ph}}{1 + \frac{1}{\ln\left(\frac{J_{Ph}}{J_S}\right)}}$$
(40)

#### and the optimal voltage becomes:

590 
$$V_{opt} = \frac{k T_m}{q} \left[ \ln \left( \frac{J_{Ph}}{J_S} \right) - \ln \ln \left( \frac{J_{Ph}}{J_S} \right) \right]$$
(41)

591 The analytical peak power is finally expressed as:

592 
$$P_{opt} = J_{opt} \times V_{opt} = \frac{J_{Ph}}{1 + \frac{1}{\ln\left(\frac{J_{Ph}}{J_S}\right)}} \times \frac{k T_m}{q} \left[ \ln\left(\frac{J_{Ph}}{J_S}\right) - \ln\ln\left(\frac{J_{Ph}}{J_S}\right) \right]$$
(42)

593

#### 594 **3.2. Working principle**

595 The module considered is an inorganic photovoltaic device represented by its band diagram

596 (Fig.9). His photon flux conversion into electrical energy is based on three mechanisms [79].

597 - the incident photons absorption by the active material constituting the device;

- electron-hole pairs creation in the semiconductor material;

599 - Collect of the charge-carriers photogenerated in the device.

600 An incident photon is absorbed in the photoactive semiconductor if the photon energy is

higher than the bandgap  $(E_g)$  of the semiconductor. This excites an electron from the valence

602 band to the conduction band leaving a positively charged hole in the valence band. The 603 electron and hole are then extracted at the contacts to the outer circuit.



#### Figure. 9. Working principle of the solar cell

A small  $E_g$  is desirable in order to absorb as many photons as possible. However for 615 photons with  $hv > E_g$  the extra energy is lost to thermodynamical relaxation [80 - 83]. 616 In general, assuming solar light generation, the lower the bandgap the higher the  $J_{SC}$ 617 and the lower the  $V_{OC}$ , hence there is some optimal bandgap that maximizes the 618 619 product of the  $J_{SC}$  and the  $V_{OC}$ . Using the principle of detailed balance, the maximum 620 achievable efficiency for a single junction solar cell at room temperature to be 44 % and the optimal bandgap to be 1.1eV [83]. Taking further losses into account they 621 furthermore showed that the highest attainable  $\eta$  for a single junction cell is 31 % 622 under practical circumstances. 623

624

614

**3.3.** Causes and effects of degradation (Visual characteristics) 625

We indexed the modes of degradation and mechanisms along with cause and effect in 626

- 627 association with the encapsulant in photovoltaic cells/modules [84]
- 3.3.1. Corrosion 628

Causes 629

- Moisture ingress through or laminate edges 630
- 631 -Presence of higher ambient temperature along with humidity
- High system voltage due to sunlight presence 632 -
- Higher ionic conductivity of encapsulant due to moisture 633 \_
- Higher moisture absorption of encapsulant 634 -

635	-	Metallization sensitivity to moisture		
636	-	Interconnect sensitivity to moisture		
637	*	Effects		
638	-	Hotspot induced backskin burns		
639	-	Hotspot induced broken glass		
640	-	Power drop beyond warranty limit due to severe series resistance		
641	*	Mechanism		
642	-	Chemical corrosion (metallic and semiconducting components during		
643		nighttime), electrochemical corrosion (metallic components during daytime), or		
644		photoelectrochemical corrosion (semiconducting components during daytrime)		
645		between cells or between cell and frame.		
646	3.	3. 2. Encapsulant delamination		
647	*	Causes		
648	-	Sensitivity of adhesive bonds to ultraviolet (uv) light at higher temperatures or		
649		to humidity in the field		
650	-	Poor adhesive bonds at the interfaces during processing (glass/encapsulant;		
651		cell/encapsulant; backsheet/encapsulant)		
652	-	Contamination from the material (excess in glass or acetic acid from		
653		encapsulant)		
654	*	Effects		
655		- Moisture ingress		
656		- Enhanced encapsulant conductivity and interface conductivity (enhanced		
657		chemical/electrochemical/photoelectrochemical corrosion)		
658		- Major transmission loss		
659		- Power drop beyond warranty limit due to optical decoupling and moisture		
660		ingress induced corrosion		
661	*	Mechanism		
662		- Photothermal reaction (interface bonds breakage due to UV and		
663		temperature)		
664		- Chemical reaction (interface bond breakage because of humidity or		
665		contaminants)		
666				

667	7 3.3. 3. Degradation Mode Slow corrosion				
668	* Causes				
669	- Moisture ingress through backsheet or laminate edges				
670	- Presence of higher ambient temperature along with humidity				
671	- High system voltage due to sunlight presence				
672	- Higher ionic conductivity of encapsulant due to moisture				
673	- Higher moisture absorption of encapsulant				
674	- Metallization(alloy) sensivity to moisture				
675	- Interconnect (alloy) sensitivity to moisture				
676	✤ Effects				
677	- Increase in series resistance and decrease in power but within warranty limit				
678	* Mechanism				
679	- Chemical corrosion (metallic and semiconducting components during				
680	nighttime), electrochemical corrosion (metallic components during daytime)				
681	between cells or between cell and frame				
682 683	<b>3.3.4.</b> Gradual electrochemical corrosion or cation migration to the				
682 683 684	<b>3.3.4.</b> Gradual electrochemical corrosion or cation migration to the semiconducteur surface/iunction				
682 683 684 685	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes</li> </ul>				
682 683 684 685 686	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> </ul> </li> </ul>				
682 683 684 685 686 686	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> </ul> </li> </ul>				
682 683 684 685 686 687 688	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690 691	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> </ul> </li> <li>Effects</li> </ul>				
682 683 684 685 686 687 688 689 690 691 692	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> <li>Series resistance increase and : or shunt resistance decrease depending on bias</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690 691 692 693	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> <li>Series resistance increase and : or shunt resistance decrease depending on bias polarity and climatic conditions</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690 691 692 693 694	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> <li>Series resistance increase and : or shunt resistance decrease depending on bias polarity and climatic conditions</li> <li>Potential induced degradation leading to power loss but within warranty limit</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690 691 692 693 694 695	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> <li>Series resistance increase and : or shunt resistance decrease depending on bias polarity and climatic conditions</li> <li>Potential induced degradation leading to power loss but within warranty limit</li> </ul> </li> </ul>				
682 683 684 685 686 687 688 689 690 691 692 693 694 695 696	<ul> <li>3.3.4. Gradual electrochemical corrosion or cation migration to the semiconducteur surface/junction</li> <li>Causes <ul> <li>Moisture ingress through backsheet or laminate edges</li> <li>Higher ionic conductivity of encapsulant due to moisture</li> <li>Higher moisture absorption of encapsulant</li> <li>Metallization (alloy) sensitivity to moisture</li> <li>Interconnect (alloy) sensitivity to moisture</li> <li>Series resistance increase and : or shunt resistance decrease depending on bias polarity and climatic conditions</li> <li>Potential induced degradation leading to power loss but within warranty limit</li> <li>Kechanism</li> <li>Electrochemical corrosion (metallic components during daytime or</li> </ul> </li> </ul>				

698		are more sensitive to electrochemical reactions under light) between cell and
699		frame
700	3.3.5	. Gradual backsheet warping /detaching/cracking/crumbling
701	*	Cause
702	-	Poor adhesion between encapsulant and backsheet
703	-	Moisture ingress through backsheet and /or laminate edges
704	-	Polymer disintegration over time
705	*	Effects
706	-	Slow power degradation (due to corrosion of cell and circuit components but
707		within warranty limit
708		
709		
710	*	Mechanism
711	-	Chemical reaction weaking interface bonds (due to higher ambient temperature
712		and / or humidity)
713	336	Cradual angangulant dissolaration
714	5.5.0	
715	*	
/16	-	Uv exposure at higher operating temperatures
717	-	Reduced breathability
718	-	Higher UV concentration
719	-	Inappropriate additives in EVA
720	*	Effects
721	-	Transmission loss Reduced current/power but may not be affecting fill factor or
722		warranty limit Cosmetic/visual change
723	*	Mechanism
724	-	Photothermal reaction (in the presence of UV and higher module temperature)
725	<b>2</b> 4 -	
726	3.4. E	lectrical parameters degradation correlated with visual degradation
727		

**Table1:** Electrical parameters influencing on PV cells performance

Parameters	dependency	Influential factor
Cell density photocurrent	Depend on	Irradiance and wavelength
$V_{oc}$	Logarithmically dependent on	illumination
Jsc	Dependent on	illunination
Fill factor	Increases by	I1/Is increase
Fill factor	Increases by	Series resistance decrease
Fill factor	Increases by	Shunt resistance increase
$V_{oc}$	Decreases by	Temperature rise
$J_{sc}$	Nearly constant by	Temperature rise
Fill factor	Decreases by	Temperature rise

731 732

In addition, we established a qualitative correlation between the electrical parameters affected and the different modes of degradation listed. However, the effect of discoloration causes loss of transmittance of the encapsulant EVA, reducing the photocurrent density  $(J_{ph})$  of the cell/module thus culminating in decreased absorption of sunlight by the photovoltaic cell/module and power loss [1, 85, 86].

738

The position of discoloration of EVA on solar cell results degradation of  $(J_{sc})$ 739 because it reduces the current flowing through the solar cell. It has been found that the 740 discoloration does not affect the fill factor (FF) and (Voc) more. However there are 741 significant effect on the  $(J_{SC})$  degradation and hence the power output (P) degradation [86, 742 87]. The corrosion of the edge, the junction box, bus-bars and interconnects cause 743 744 the degradation of the PV modules peak power ( $P_{max}$ ). The rate of power degradation is 745 more in case of high corrosion of string interconnect ribbon. Then, with increase of 746 percentage defects, the rate of power degradation increases. More recently, [87] shown that the power degradation range in Bus-bar is 0-2.1%/year, in cell interconnection ribbon is 0-747 2.1%/year and in string interconnection ribbon is 1-2.3%/year. The range of power 748 749 degradation varies from 2.08% to 3.48%/year and the average degradation has been 750 2.60%/year in the case of EVA discoloration for only seven PV modules analyzed.

Delamination in the back-sheet of the PV module reduces the thermal conductivity
locally and hence increases the cells/modules temperature.

753 We revealed that the delamination depends on the detachment of the two layers, EVAglass and EVA-back-sheet. The delamination occurring in back-sheet, the range of 754 power degradation varies from 3.17 to 3.63%/year [86-88]. Hot spot occurs in PV 755 modules due to thermal expansion/contraction of interconnection, shadowing, faulty 756 cell and low resistance cell resulting decrease in  $(J_{SC})$  and power. As the daily 757 758 average power increases with decrease in number of hot spots, the range of the power degradation has been 0.29%/year for no hot spot and 2.16%/year for four hot 759 spot and total power degradation after 22 years outdoor exposure has been 6.38% for 760 no hot spot and 47.52% for four hot spot [87]. As a result, while a number of hot spot 761 762 increases the area covered by the hot spot also increases.

In a general way, environmental and climatic conditions in which the modules are exposed significantly influence degradation. PV-module performance in general depends on solar irradiation (intensity, spectrum, especially ultraviolet (UV) radiation), temperature, moisture, mechanical stresses; and electrical operating conditions [89]. Other regional climate factors must be considered: snow, hail, wind, salt, sand, dust, and pollutants/gases, some of which are potentially corrosive.

Temperature is extremely significant to the degradation process, especially hot spots, encapsulant bleaching, delamination failure on interconnections, etc. Temperature is responsible for most of the chemical reactions of the degradation of modules. Elevated temperatures can drastically change the mechanical, electrical, and optical properties of polymeric materials. Rapid changes in temperature over a short period of time cause thermo-mechanical stress and induce defects that can alter critical properties of polymer [87-89].

The long-term damage to the EVA during its useful life often involves interaction between heating at temperatures above 50°C, absorption of moisture, oxygen, and most importantly, ultraviolet (UV) radiation from the solar spectrum. UV radiation has been identified as a critical factor in the degradation of photovoltaic modules by many research groups, and chemical changes in its structure have been identified leading to changes in transmission (discoloration). Thus, photodegradation caused by UV radiation is a major degradation of the material exposed to direct sunlight, and degradation is certainly climate zone dependent since the solar spectrum can change significantly from one geographical area to another [84-89]. 

#### **3. 5. Numerical Simulation (Temperature effect)**

Servant model is based on the heat exchange between the PV module and the atmosphere. It allows obtaining the temperature of the module according to meteorological parameters Eq. (21) [76].

790 
$$T_m = T_{amb} + d \times G(1 + e \times T_{amb})(1 - f \times W)$$

where W: Wind speed and d, e, f: Empirical parameters;  $T_{amb}$ : ambient temperature. 

#### **3.3.1.** Photocurrent Density $(J_{ph})$

$$J_{ph}(G,T) = J_{ph_{ref}} \left[ 1 + \alpha_{J_{SC}} \left( T_m - T_{ref} \right) \right] \frac{G}{G_{ref}}$$

$$J_{ph}(T_{amb}) = \frac{GJ_{ph_{ref}}}{G_{ref}} \left[ 1 + \alpha_{J_{SC}} \left( T_{amb} + d \times G(1 + e_0 T_{amb})(1 - f_0 W) - T_{ref} \right) \right]$$
$$= \frac{\alpha_{J_{SC}} \cdot G \cdot J_{ph_{ref}}}{G_{ref}} \left[ \frac{1}{\alpha_{J_{SC}}} - T_{ref} + T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_0 W) \right]$$

#### Variables declaration:

$$\begin{aligned} & 799 \quad J_{phref} = 5.11A/m^2; \ G_{ref} = 1W/m^2; \ G = 80:10:1000 \ W/m^2 \\ & 800 \quad \alpha_{Jsc} = u = 7.5 \times 10^{-2}; \ T_{ref} = 298 \ \text{K}; \ d = 2.1 \times 10^{-2} \ ^\circ C.m^2/w; \\ & 801 \quad e_0 = 1.6.10^{-2^0}C^{-1}; \ f_o = 7.5 \times 10^{-2}; \ W = 1.1 \times 10^{-3} \ m/S \\ & 802 \quad t = \frac{u \times G \times J_{phref}}{G_{ref}}; \ p = \frac{1}{u}; \ t_1 = p - T_{ref}; \ S = d \times G \times (1 - f_o \times W) \\ & 803 \qquad \qquad J_{ph}(T_{amb}) = t \times [t_1 + T_{amb} + S \times (1 + e_0 \times T_{amb})] \end{aligned}$$
(43)

#### **3.3.2.** Series resistance $(R_s)$

806 
$$\frac{R_S}{R_{S_{ref}}} = \frac{T_m}{T_{ref}} \left( 1 - \beta \times ln \frac{G}{G_{ref}} \right)$$

807 
$$R_{S}(Tamb) = R_{S_{ref}} \times \frac{T_{m}}{T_{ref}} \left( 1 - \beta \times ln \frac{G}{G_{ref}} \right)$$

808 
$$T_m = T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_o W)$$

809 
$$R_{S}(Tamb) = \frac{R_{S_{ref}}}{T_{ref}} (T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_o W)) \left(1 - \beta \times \ln \frac{G}{G_{ref}}\right)$$

810 Variables declaration:

811 
$$Rs_{ref} = 5.11 \ \boldsymbol{\Omega}$$
;  $T_{ref} = 298 \ K$ ;  $u = \beta = 4.5. \ 10^{-1}$ ;  $G = 80: 10: 1000 \ W/m^2$ 

812 
$$d = 2.1 * 10^{-2} °C. m^2/w$$
;  $G_{ref} = 1w/m^2$ ;  $e_0 = 1.6.10^{-2^0}C^{-1}$ ;  $f_o = 7.5 \times 10^{-2}$ ;

813 
$$W = 1.1 \times 10^{-3} m/S$$
;  $t_1 = \frac{R_{S_{ref}}}{T_{ref}}$ ;  $V = \frac{G}{G_{ref}}$ ;  $t_2 = (1 - u \times \ln(V))$ 

814 
$$t = \mathbf{t_1} \times t_2$$
 and  $S = d \times G \times (1 - f_o W)$ 

$$R_{S}(Tamb) = t \times (T_{amb} + S \times (1 + e_{0} \times T_{amb}))$$
(44)

.

815 816 817

#### **3.3.3.** PV module efficiency $(\eta)$ 818

$$\eta = \eta_{T_{ref}} [1 - \beta_{ref} (T_m - T_{ref}) + \gamma \times \log G_T]$$
819
$$T_m = T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_o W)$$

$$\eta = \eta_{T_{ref}} [1 + \gamma \times \log (G) + \beta_{ref} \times T_{ref} - \beta_{ref} \times (T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_o W))]$$

#### 820 Variables declaration :

821 
$$T_{ref} = 298 \,^{\circ}K$$
;  $d = 2.110^{-2}C.m^2/w$ ;  $e_0 = 1.5.10^{-2^0}C^{-1}$ ;  $\beta_{ref} = V = 4.5 \times 10^{-3}$ ;  $n_{ref} = 1.5 \times 10^{-1} \,\%$ ;  $\gamma = u = 5.3 \times 10^{-4}$ ;  $G = 80:10:1000 \, w/m^2$ 

823 
$$f_o = 7.5 \times 10^{-2}; W = 1.1 \times 10^{-3} m/S$$

824 
$$t = 1 + u \times \log(G)$$
;  $t_1 = V \times T_{ref}$ ;  $t_2 = t + t_1$ ;  $S = d \times G \times (1 - f_o W)$ .

825 
$$\eta (Tamb) = \eta_{T_{ref}} \times [t_2 - V \times (T_{amb} + S \times (1 + e_0 \times T_{amb}))]$$
 (45)

826

#### **3.3.4.** PV module power output (P) 827

T

т

828 
$$P(Tamb) = G \times \tau_{pV} \times \eta_{ref} \times A \times [1 - V \times (T_m - T_{ref})]$$

829

$$T_m = T_{amb} + d \times G \times (1 + e_0 \times T_{amb})(1 - f_o W)$$
$$p(Tamb) = G_T \tau_{pV} \eta_{ref} A [1 + V \times T_{ref} - V]$$

$$\times (T_{amb} + d \times G \times (1 + e_0 \times T_{amb})(1 - f_o W))]$$

#### 830 Variables declaration:

831 
$$G = 80:10:1000 W/m^2$$
;  $n_{ref} = 1.5.10^{-1}\%$ ;  $\tau_{pV} = u = 3.8.10^{-1}$ ;  $A = 4$ ;

 $V = 4.5 \times 10^{-3}$ ;  $d = 2.1 \times 10^{-2} Cm^2/w$ ;  $T_{ref} = 298 K$ ; 832  $e_0 = 1.5 \times 10^{-2} \circ C^{-1}$ ;  $f_0 = 7.5 \times 10^{-2}$ ;  $W = 1.1 \times 10^{-3} m/S$ 833  $p_1 = A \times G \times u \times \eta_{ref}$ ;  $t = 1 + V \times T_{ref}$  and  $S = d \times G \times (1 - f_o W)$ . 834  $p(Tamb) = p_1 \times [t - V \times (T_{amb} + S \times (1 + e_0 \times T_{amb}))]$ 835 (46)836 **3.3.5.** Shunt resistance  $(R_{Sh})$ 837  $R_{sh} = R_{sho} - m_o \times T_m$ 838  $T_m = T_{amb} + d.G(1 + e_0T_{amb})(1 - f_0W)$ 839  $R_{Sh}(Tamb) = R_{Sho} - m_o[T_{amb} + d.G(1 + e_0T_{amb})(1 - f_oW)]$ 840  $R_{Sh}(Tamb) = m_o \times \left[\frac{R_{Sho}}{m_o} - T_{amb} - d \times G \times (1 + e_0 \times T_{amb})(1 - f_o W)\right]$ 841 Variables declaration: 842  $m_o = 6.8936 \,\Omega C m^2 / K; R_{sho} = 3858.86 \,\Omega C m^2 / K; d = 2.1 \times 10^{-2} C \cdot m^2 / w;$ 843  $G = 80:10:1000 \ w/m^2$ ;  $e_0 = 1.5 \times 10^{-2^0} C^{-1}$ ;  $f_o = 7.5 \times 10^{-2}$ ; 844  $W = 1.1 imes 10^{-3} \ m/S$  ;  $u = rac{R_{ShO}}{m_o}$  and  $S = d imes G imes (1 - f_o W)$ 845  $R_{Sh}(Tamb) = m_0 \times [u - T_{amh} - S \times (1 + e_0 \times T_{amh})]$ 846 (47)847 848 849 **3.3.6.** Open-circuit voltage (V<sub>oc</sub>) 850  $V_{OC}(Tamb) = \frac{E_g}{a} - \frac{nkT_m}{a} \times \ln\left(\frac{J_S}{L_{rb}}\right)$ 851  $T_m = T_{amb} + d \times G(1 + e_0 \times T_{amb})(1 - f_0 W)$ 852  $V_{oc}(Tamb) = \frac{E_g}{q} - \frac{nk}{q}(T_{amb} + d \times G \times (1 + e_0 \times T_{amb})(1 - f_0 W)) \times \log\left(\frac{J_s}{I_{oc}}\right)$ 853 Variables declaration: 854  $Eg = 1.884 \times 10^{-19}$  Joule; n = 1.25;  $q = 1.6.10^{-19}C$ ;  $J_{nh} = 5.11 \, A/m^2$ ; 855  $J_s=0.9\,A/m^2$  ;  $G=80{:}\,10{:}\,1000W/m^2$  ;  $k=1.38\times 10^{-23}$  ; 856  $d = 2.1 \times 10^{-2} C. m^2 / w$ ;  $e_0 = 1.5 \times 10^{-2} \circ C^{-1}$ ;  $f_0 = 7.5 \times 10^{-2}$ ; 857  $W = 1.1 \times 10^{-3} \, m/S$ ;  $t = \frac{n \times k}{q}$ ;  $u = \frac{J_S}{J_{nh}}$ ;  $p = \log(u)$ ;  $t_1 = \frac{E_g}{q}$ ; 858

859  $S = d \times G \times (1 - f_o \times W)$ ;  $t_3 = p \times t$  and  $t_4 = \frac{t_1}{t_3}$ 

860  
861 
$$V_{oc}(Tamb) = t_3 \times (t_4 - T_{amb} - S \times (1 + e_0 \times T_{amb}))$$
 (48)

#### 863 **3.3.7. Saturation current density** $(J_S)$

$$J_{S} = J_{S_{ref}} \times \left(\frac{T_{m}}{T_{ref}}\right)^{\frac{3}{ni}} \times exp\left(\left(\frac{E_{g}(T)}{n \times K}\right)\left(\frac{1}{T_{ref}} - \frac{1}{T_{m}}\right)\right)$$

 $T_m = T_{amb} + d \times G \times (1 + e_0 \times T_{amb})(1 - f_o W)$ 

864

$$J_{S} = J_{S_{ref}} \times \left(\frac{T_{amb} + d \times G \times (1 + e_{0} \times T_{amb})(1 - f_{o}W)}{T_{ref}}\right)^{\frac{3}{n}} \times exp\left(\left(\frac{E_{g}(T)}{n \times K}\right)\left(\frac{1}{T_{ref}} - \frac{1}{T_{amb} + d \times G \times (1 + e_{0} \times T_{amb})(1 - f_{o}W)}\right)\right)$$

865 Variables declaration:

866 
$$J_{ref} = 1.2.10^{-3} A/m^2$$
;  $T_{ref} = 298 \,^{\circ}K$ ;  $d = 2.1 \times 10^{-2} \,^{\circ}C \times m^2/w$ ;

867 
$$G = 80: 10: 1000 W/m^2$$
;  $e_0 = 1.5 \times 10^{-2} \circ C^{-1}$ ;  $f_o = 7.5 \times 10^{-2}$ ;

868 
$$W = 1.1 \times 10^{-3} m/S$$
;  $n = 1.25$ ;  $E_g(T) = 1.884 \times 10^{-19}$  Joule;

869 
$$k = u = 1.38 \times 10^{-23}$$
;  $u = \frac{3}{n}$ ;  $t = \frac{E_g(T)}{n \times k}$ ;  $t_1 = \frac{1}{T_{ref}}$ ;  $s = d \times G$ ;

870 
$$z = 1 - f_o \times W$$
;  $t_2 = s \times z$  and  $t_3 = t_1 \times t_2$ 

$$J_{S}(T_{amb}) = J_{S_{ref}} \times \left(t_{1} \times T_{amb} + t_{3} \times (1 + e_{0} \times T_{amb})\right)^{u}$$
$$\times exp\left(t \times \left(t_{1} - \frac{1}{T_{amb} + t_{2} \times (1 + e_{0} \times T_{amb})}\right)\right)$$
(49)

872

871

#### **3.4. Interpretation of the results simulated**

It is necessary to study the performance of solar cells under variable solar irradiance intensities and temperatures in order to be able to provide the accurate prediction of the energy production of PV systems. In this study, the dependence of performance parameters  $(J_{Ph})$ ,  $(R_S)$ ,  $(V_{OC})$ ,  $(R_{Sh})$ , (P), ( $\eta$ ) and ( $J_S$ ) under the illumination intensity of 1000  $W/m^2$  at different temperatures is shown in **Fig.10** to **Fig.16**. The parameters ( $V_{OC}$ ) (Fig.10), ( $R_{Sh}$ ) (Fig.11), and ( $\eta$ ) (Fig.12), decrease linearly with T while ( $R_S$ ) (Fig.13) increase linearly with ambient temperature.









1009 1010 Globally, we note a small increase in saturation current density  $(J_s)$  by 3.8% and 1011 15.76% with temperature, which can be attributed to the increased light absorption owing to a decrease in the bandgap of silicon. The decrease of  $(\eta)$  with temperature is 1012 mainly controlled by the decrease of  $(V_{OC})$  and fill factor (FF) with T. It can be seen 1013 that with the temperature increasing, the  $(J_{SC})$  increases slightly and the  $(V_{OC})$ 1014 decreases strongly. The slight increase of  $(J_s)$  in this study, similar to the effects of 1015  $(J_{SC})$  originates from the narrowing of the band gap along with the increase in the 1016 1017 number of phonons and density of states in the conduction and valence bands, while 1018 the strong decrease in the  $(V_{0C})$  is mainly linked to the increase of the leakage current [90]. For a standard solar cell, the  $(J_{SC})$  can be strongly influenced by the minority 1019 1020 carrier diffusion length which depends on the product of the minority electron mobility and carrier lifetime. In addition, the rate of decrease of  $(V_{OC})$  is 7.8% and is 1021 1022 much larger in magnitude than decrease of Rs with T. The rate of decrease in the 1023 maximum output power (P) is 50.75% while that of the efficiency ( $\eta$ ) is about 1024 22.82%. This result is very significant in our work because, the effect of heat and irradiance are the factors that negatively affect the overall performance of PV cells. 1025 1026 Moreover, the impact of non-linearity of the  $(J_s)$  (Fig.17) with irradiance or T in this study is very small for silicon solar cell. 1027

Fig.17. Overall Statistical Results

1028

#### 1029 4. Conclusions and perspectives

We study analytically the electrical parameters ( $J_{Ph}$ ,  $R_S$ ,  $V_{OC}$ ,  $R_{Sh}$ ,  $\eta$ ,  $J_S$  and P) degradation of monocrystalline silicon PV cells/modules under temperature and heat effect. We exploited the Servant model, using the wind velocity under standard irradiation conditions (G=80:10:1000 w/m<sup>2</sup>) in the 298-353K temperature range. Next, the single exponential model has been used to extract the PV cell parameters from a single (*J*–*V*) characteristic curve at various values of T. Finally, the different failure modes of PV cells/modules induced by heat and temperature have been indexed.

1037 Our results reveal that:

1038 - Delamination of encapsulant and back sheet,

Bubble formation, Oxidation of busbars, Yellowing / browning of encapsulants
and back sheets with and without power loss,

1041 - Discoloration of busbars,

1042 - Corrosion of connections,

1043 - Cracking of back sheet,

Hot spots, Cell breakage and micro cracks are the dominant modes of
 degradation. Temperature is responsible for most of the chemical reactions of
 the degradation of modules.

The numerical simulated show that  $(J_{Ph})$  increase exponentially from 7.67% to 65.87% with temperature.  $(R_S)$  increase linearly by 7.6% and 9.18% while  $(V_{OC})$ decrease from 19.4% to 17.6% and  $(R_{Sh})$  decrease approximately by 12.6% and 4.8%. The power output (P) losses decreases by 82.31% and 31.56%, and the overall linear losses in efficiency ( $\eta$ ) has been approximately 27.84% and 5.02%, while  $(J_S)$ increase exponentially from 3.87% to 15.75%.

In definitive, the increase in  $(J_{ph})$  with temperature can be attributed to the increased in light absorption owing to a decrease in the bandgap of silicon. The decrease in  $(\eta)$ with temperature is mainly controlled by the decrease in  $(V_{oc})$  and fill factor (FF) with T. Elevated temperatures can drastically change the mechanical, electrical, and optical properties of polymeric materials, as a result, a drop of the PV cells/modules overall efficiency.

1059 Future work can be about:

1060 1- Extensions to the model,

- 1061 2- Improvement of the analytical results,
- 1062 3- Compare experimental results obtained by Mattei model with those obtained1063 analytically
- 4- Compare analytically Servant model with Mattei model.
- 1065

1066

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